

## The ATLAS Inner Tracker detector for the High-Luminosity LHC upgrade

#### Outline

- The HL-LHC upgrade & challenges for detectors
- The ATLAS Inner Tracker (ITk) design and performance
- ITk detector modules
  - Sensor development
  - Readout electronics design
- Lightweight services
- ITk production
- Conclusion

#### LHC and ATLAS



#### The High-Luminosity LHC

#### CERN Accelerating science



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#### Ground-breaking ceremony for the High-Luminosity LHC

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Posted by Corinne Pralavorio on 26 Jun 2018. Last updated 26 Jun 2018, 16.21. *Voir en français* 



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# The High-Luminosity LHC



- Higher energy and luminosity benefit searches for new particles, precision measurements and study of rare processes but pose severe challenges to the detectors
- The vertex and tracking detectors, being the closest to the IP, will need significant upgrade

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#### Particle density and data rate

With an instantaneous peak luminosity up to 7.5 x 10<sup>34</sup> cm<sup>-2</sup>s<sup>-1</sup> the mean number of interactions per bunch crossing (i.e. every 25 ns) is 200 (pile-up) → high particle density and data rate



 Finely segmented detectors and fast readout electronics are needed to keep low hit occupancy [hits/cm<sup>2</sup>/sec]

#### **Radiation levels**

- The integrated luminosity of 4000 fb<sup>-1</sup> results in x10 radiation damage with respect to LHC
  - Fluence up to 1.3 x 10<sup>16</sup> 1 MeV  $n_{eq}/cm^2$
  - Total Ionising Dose up to 10MGy = 1 Grad



Radiation hard technologies for sensor and electronics

# More challenges

#### Material budget

- Multiple scattering and nuclear interactions in tracker material limit tracker and calorimeter performance
- Dominant source of material are services and support structures



- Hermeticity and sufficient number of hits over large angular acceptance
  - Particles originating from within the 30cm-long beam spot should hit a sensor in each layer they traverse
  - A high number of hits is needed for good tracking efficiency but a tradeoff with the amount of material has to be found
- Cost should be minimised
- All these challenges have to be met while keeping the same tracking performance of the current ATLAS tracking detector

#### ATLAS tracker upgrade

- The current ATLAS Inner Detector (ID) needs to be replaced for the HL-LHC
  - Severe radiation damage to all components
  - TRT technology cannot cope with hit occupancy
- ATLAS is planning a new all-silicon Inner Tracker (ITk) using state-of-the-art silicon technologies and optimised design of all detector components



## ITk layout

- Pixel detector
  - Cover to  $\eta = 4.0$
  - 13 m<sup>2</sup> of silicon sensors
  - Design optimised to **improve hit coverage with less material** 
    - Inclined modules
    - Endcap-ring system
  - Two innermost layers designed to be replaceable to cope with radiation environment



#### ITk layout

- Strip detector
  - Cover to  $\eta$  = 2.7
  - 165 m<sup>2</sup> of silicon sensors
  - 4 barrel layers and 6 endcap
  - Modules loaded on both side of support structure with small stereo angle giving the second coordinate measurement



#### ITk material budget

- The material of the ITk is significantly less than for the ID at almost all  $\eta$
- The main drivers for the improvement are
  - Thinner silicon
  - Innovative power distribution schemes
  - Optimized routing of services
  - Rigid mechanical structure with lightweight carbon foam core



# ITk track parameters resolution

- Longitudinal impact parameter resolution (pile-up rejection)
  - Improved by pixel finer segmentation in z (50 $\mu m$  instead of 250 $\mu m$ )
- Transverse impact parameter resolution (btagging)
  - Worse resolution at high  $p_T$  due to larger radius of inner pixel layer (39mm instead of 33.5mm; radiation and data rate prohibitive at smaller radii)
- Transverse momentum resolution
  - Improved by almost a factor 2 thanks for the higher precision of the strip detector wrt. TRT
- Lower material benefits all track parameters resolution



#### ITk detector modules

#### Silicon detector technologies for the ITk



Hybrid pixel detector concept

Flex

- Developed for operation at the LHC
- Baseline concept for ITk pixel detector

Sensor

Optimised sensor design

FEIx

- New CMOS technology for the readout chip
- Sensor and readout electronics are separate entities connected via fine pitch bump bonds

Stave surface

- Each pixel is connected to one readout channel in the FE chip

Wire-bond

- Expensive, non-commercial hybridization process
- Electrical interface, flex, glued on sensor backside
  - Hosts passive components and auxiliary chips (i.e. for data aggregation and transmission)



# DMAPS in commercial CMOS technology





- Monolithic active pixels sensors (MAPS)
  - Sensor and readout electronics in the same substrate
  - Originally developed for low rate applications (STAR and ALICE ITS)
- Recent development with commercial CMOS technologies improve radiation-hardness and high rate capability 
   → Depleted MAPS
- No hybridisation and advantages of commercial fabrication process
   → low cost and ease of construction
- Candidate technology for pixel outermost layer

#### Strip detector module

- Hybrid concept with separated sensor and readout electronics
- Two electrical interfaces, hybrid flex and power board, glued on the sensor front-side
- Readout ASICs and data aggregator chip are glued on the hybrid flex and wire bonded to the sensor
  - Each strip is connected to one readout channel in the FE chip
- Power distribution is provided via the power board



## Module types in the ITk

- To provide hermetic coverage, different module configurations are need resulting in a large number of different sensors and hybrid/flex flavours
- Pixel modules can be single, dual, or quad depending on whether the sensor is bump bonded to one, two, or four FE chips
- Strips



Sensor development

#### Radiation tolerant silicon sensors

- High energy particles introduce complex lattice defects in the silicon bulk, i.e. energy levels in the silicon band gap
- Increased leakage current
  - Shot noise
  - Temperature increase → higher leakage current → need to cool sensors to avoid thermal runaway
- Change in effective doping concentration
  - Change in charge collection volume
- Charge trapping
  - Smaller sensor signal

	Max fluence [1 MeV n <sub>eq</sub> /cm <sup>2</sup> ]
Pixel	1.3 x 10 <sup>16</sup>
Strip	1.2 x 10 <sup>15</sup>

To mitigate these effects charge should be collected by drift

#### Drift based silicon sensors

- Drift based silicon sensors work as a reverse biased pn-junction
- Low doped, i.e. high resistivity, silicon bulk with highly doped collection electrodes
  - The segmentation (pitch, d) of the contacts defines the **spatial resolution** (σ)
- High (reverse) bias voltage (V<sub>bias</sub>)
  - Depletion grows into the substrate
  - Electric field
- Traversing charged particles create e-/h+ pairs
- Movement of charges (i.e. drift in electric field) towards the electrodes generates a signal
  - Large collected charge, fast charge collection, radiation-hard

#### Cross section of a silicon sensor





#### Planar pixel and strip sensors

- **n-in-p** configuration for both strips and pixels
  - In the ID strips are p-in-n and pixels n-in-n
  - Signal from electrons faster than holes
  - One sided process, simpler and cheaper than n-in-n
- Optimised design of bias structure and edge region to obtain uniform electric field
- Pixel pitch 50 x 50 or 25 x 250 μm<sup>2</sup>, thickness 100-150 μm
- Strip pitch 75 μm x 25-50 mm, thickness 300-320 μm







#### 3D sensors

- Alternative geometry for pixel sensors that provides higher radiation tolerance by design: drift path decoupled from particle path
  - First application in the IBL detector
- Electrodes penetrate vertically in the sensor bulk
  - Shorter charge collection distance  $\rightarrow$  less charge trapping
  - High field with low voltage → lower power, i.e. heat, after irradiation
- Technology of choice for pixel inner layer

	IBL	HL-LHC	
Pixel size [µm <sup>2</sup> ]	50 x 250	50 x 50	25 x 100
Electrode config	2E	1E	2E
Electrode spacing [µm]	67	35	27
Thickness [µm]	230	230	
Rad-hard [1MeV n <sub>eq</sub> /cm <sup>2</sup> ]	9 x 10 <sup>15</sup>	1.4 x 10 <sup>15</sup>	





#### **CMOS** sensors

- Recently commercial CMOS technologies have become available with HV capability on HR substrate
  - Imaging sensors market
- CMOS sensors investigated as a possible replacement of traditional silicon sensors for hybrid pixels or to develop DMAPS detectors for the pixel outmost layer
  - Significant advantages in terms of cost and large area production
  - Demonstrated adequate radiation tolerance



#### Readout electronics design

#### **Readout electronics**

- Basic functionality
  - The signal from pixel and strip sensors is integrated, amplified and digitized by the FE chip
  - The FE chips stores the hit information and sends it to the detector data acquisition system upon arrival of the trigger signal
  - Different readout architectures are developed based on the rate and radiation levels
- To cope with the high hit rate, fast readout with high logic density (i.e. memory) is needed
- Smaller feature size CMOS technologies are used for the ITk
  - **65 nm** CMOS for the pixel FE (130 and 250 nm in ID pixel)
  - 130 nm CMOS for the strip FE (250 nm in ID strip)

#### Radiation hardness of CMOS technologies

- Total ionising dose effects
  - Charge trapping in thick isolation oxides and at the oxide-silicon interfaces lead to degradation of the performance of MOSFETs transistors
  - Dependent on dose rate and temperature history of the FE (annealing)
- Single Event Effects, **SEE** 
  - Local ionisation effects that change the status of memory cells
- Deep submicron CMOS technologies provide adequate radiation tolerance provided mitigation strategies are put in place
  - Pixel innermost layers will be replaced after 2000 fb<sup>-1</sup>
  - Strip detector operational T profile devised to reduce the effects of TID
  - Triplicated logic and reset schemes to protect against SEE

	TID [Mrad]		
Pixel	10 <sup>3</sup>		
Strip	50		

#### Readout for HL-LHC innermost layers

- Very innovative design based on a new readout architecture
- Analog "islands" in a digital synthesized "sea"
- Collection of large digital cores containing many regions
  - Complex functionality in the pixel matrix
  - Resources shared among many pixels
- 2 dimensional digital connectivity
- Smart clustering in the pixel matrix to send most information with least bandwidth (5.12 Gbps/chip)



#### Strip FE readout chip: ABCStar

- 256 readout channels with binary readout
- Design compatible with multi-level trigger scheme (increased buffering per channel)
  - Single Level- 0 trigger (L0) at 1 MHz with a maximum latency of 10  $\mu$ s
  - L0-L1 trigger: information from ITk used as input for a second level L1 trigger signal combined with calo and muon data
  - L0 readout at 1 MHz for 10% of the modules belonging to the Region of Interest (RoI) identified at L0, followed by full read-out at L1 at 400 kHz
- LCB protocol
  - L0, commands, and bunch crossing ID sent in one encoded data stream designed to allow triggering on 4 consecutive bunch crossings
- L0 tag
  - The L0ID is generated by the DAQ and attached as a tag to the L0
  - Modules receive the L0ID and send back data with this identifier
  - Errors affect only one frame (i.e. 4 triggers)
  - No need for synchronized counters in chip and DAQ

#### Strip FE TID characterization

- Low temperature, low dose rate irradiations show a current evolution with TID compatible with the radiation induced narrow channel effect typical of 130 nm CMOS technology node
  - Current increase due to positive charge trapped in the later STI
  - Current decrease due to later built-up of negative interface states
  - Effect well characterised, model available to predict current peak at different T and dose rate
- FE noise increase with TID mitigated by the use of enclosed layout transistors



#### Lightweight services

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#### Power distribution

 Tracking detectors for high rate environments are power hungry devices → high current consumption



- Traditional tracking detectors power distribution scheme
  - Each module is powered independently with a constant voltage
  - High number of long cables with large cross section
  - At the LHC cable channels are saturated, services dominate the material budget, power efficiency is below 50%
- Readout electronics design for the HL-LHC optimises power consumption against rate requirements but given the larger number of detector channels, the power consumption will be higher than then ID → New powering schemes are needed to reduce the transmitted current
  - Serial powering for the pixel detector
  - DC-DC conversion for the strip detector

## Serial powering for pixels

- Current based powering scheme
  - N nodules are powered in series by a constant current = current for one module
  - Voltages are generated by regulators on-chip
- Wrt. a conventional voltage based powering scheme the transmitted current scales of a factor N: I → I/N
  - Smaller cable cross section
  - Reduced power losses on the cables
- Number of modules in the chain is a trade-off between redundancy, quality of data transmission, and amount of cables
- Dedicated developments
  - Integrated regulator to convert input current to stable voltage for FE chips, Shunt-LDO
  - Bypass chip to disconnect faulty modules from the chain
  - Both need to meet the radiation requirements



#### **DC-DC** conversion

- Power transmitted at high voltage and low current to the modules
- x2 DC-DC buck converter on module
  - Radiation-hard tolerant converter development by CERN PH-ESE group
- Optimised integration of regulator and coil on power board to shield module from EMI
  - Solenoidal flat coil geometry to fit into available space
  - Shield made of a mix of aluminium and copper
  - Demonstrated electric and magnetic fields shielding whilst still maintaining a target efficiency of 75% at the nominal load of 2 A



#### ITk production

- And

#### Production of a 200m<sup>2</sup> silicon tracker

- The production of the ATLAS ITk is a challenge as much as the R&D to identify the right technologies and design for the components
- Quality control and quality assurance
  - Assure component reliability in extreme experimental conditions
  - Monitor rate and quality of production to detect problems that may arise and stop production
- Industrialised production flow
  - Common tooling development and assembly procedures
- Database
  - Store information from all detector elements QC and QA during production
  - Track the geographic location and utilisation of all parts during construction
  - Debugging of faulty conditions during operation

#### Conclusion

- To benefit from the physical potential of the HL-LHC the ATLAS experiment is preparing the replacement of its inner tracking system
- The new, all-silicon Inner Tracker (ITk) maintains and in some cases improves the tracking performance of the ATLAS detector while coping with 200 pile-up events per collision
- Radiation tolerant sensor and readout electronics prototypes have demonstrated the required functionality
- Production is due to start in 2020 for the strip detector and in 2021 for the pixel detector. The 200m<sup>2</sup> ITk detector will be produced in three years.